

**Search Notes**

Application/Control No.

10/764,647

Examiner

Rachna Singh

Applicant(s)/Patent under  
Reexamination

TRAN, BAO

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	501.1	2/22/2006	RS
715	513	2/22/2006	RS
707	2	2/22/2006	RS
Above	Updated	6/12/2006	RS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (US-PGPUB; USPAT; JPO; EPO; DERWENT; IBM-TDB)	2/22/2006	RS
ACM Database	2/22/2006	RS
East (US-PGPUB; USPAT; JPO; EPO; DERWENT; IBM-TDB) - Text Search Attached	6/12/2006	RS